EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	50	("5698876" "5475646" "5808947" "4320881" "5818772" "5861660" "5883008" "5991212" "6005628" "4597080" "4841485" "4893072" "4918594" "5331164" "5473551" "5477492" "5495268" "5525912" "5606568" "5636163" "5724289" "5737342" "5742785" "5826007" "5930187" "6006350" "6065142" "6112067" "6208570" "6233701" "6243576" "3579199" "4166029" "4257261" "4261040" "4266292" "4287594" "4293950" "4306303" "4312067" "4323972" "4330838" "4334307" "4360911" "4369511" "4370641" "4387587" "4398284" "4422098" "4429368").pn.	USPAT	OR	ON	2006/03/29 13:24
S2	16	S1 and (redundant repair replace) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:13
S3	164569	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:14
S4	105247	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested) and (fail error erroneous failure failing failed bad)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:15
S5	18449	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested) and (fail error erroneous failure failing failed bad) and row and column	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:16
S6	4605	(compare compared comparing comparison) and (redundant repair replace) and (test testing tester tested) and (fail error erroneous failure failing failed bad) and row and column and (test with generat$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:18
S7	3	S1 and S6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:18

S8	5	"6421286"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:48
S9	2	"20040205427"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/29 13:48

EAST Search partially lost

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           (c) 2006 Elsevier Eng.  Info. Inc.
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File   60:ANTE: Abstracts in New Tech & Engineer 1966-2006/Aug
           (c) 2006 CSA.


Set     Items    Description
S1      108621   "TEST"()(VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR S-
                 EQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR S-
                 IGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2         176   SCAN(1W)VECTOR? ?
S3      817717   CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR -
                 PCB OR SOC
S4        7316   (SECOND? OR 2ND OR ANOTHER OR OTHER OR DIFFERENT OR SEPARA-
                 TE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINAT-
                 ION)(2W)S3
S5     17071040  ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR A-
                 NOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT?
                 OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GO-
                 OD OR CORRECT?? OR PROPER?
S6      3205661  S5(10N)(DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANA-
                 LYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES
                 OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND???? OR COMP-
                 UTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7      2366280  S5(10N)(GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN?
                 OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR
                 INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8          27   S1:S2(20N)S4
S9           6   S8 AND S6:S7
S10          4   RD  (unique items)
```

File 275:Gale Group Computer DB(TM) 1983-2006/Aug 29
        (c) 2006 The Gale Group
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        (c) 2006 Dialog
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Set	Items	Description
S1	43744	"TEST"()(VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR S-EQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR S-IGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2	242	SCAN(1W)VECTOR? ?
S3	1169148	CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR -PCB OR SOC
S4	32911	(SECOND? OR 2ND OR ANOTHER OR OTHER OR DIFFERENT OR SEPARA-TE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINAT-ION)(2W)S3
S5	11966100	ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR A-NOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT? OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GO-OD OR CORRECT?? OR PROPER?
S6	1537459	S5(10N)(DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANA-LYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND???? OR COMP-UTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7	947776	S5(10N)(GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN? OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8	37	S1:S2(20N)S4
S9	19	S8(100N)S6:S7
S10	12	RD (unique items)

Set	Items	Description
S1	36679	"TEST"()(VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR S-EQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR S-IGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2	60	SCAN(1W)VECTOR? ?
S3	722618	CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR -PCB OR SOC
S4	13005	(SECOND? OR 2ND OR ANOTHER OR OTHER OR DIFFERENT OR SEPARA-TE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINAT-ION)(2W)S3
S5	6292563	ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR A-NOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT? OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GO-OD OR CORRECT?? OR PROPER?
S6	317246	S5(10N)(DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANA-LYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND???? OR COMP-UTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7	648372	S5(10N)(GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN? OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8	69	S1:S2(20N)S4
S9	19	S8 AND S6:S7
S10	9	S9 AND AC=US/PR AND AY=(1963:2002)/PR
S11	15	S9 AND AC=US AND AY=1963:2002
S12	15	S9 AND AC=US AND AY=(1963:2002)/PR
S13	10	S9 AND PY=1963:2002
S14	16	S10:S13

Set	Items	Description
S1	28808	"TEST"()(VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR S-EQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR S-IGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2	126	SCAN(1W)VECTOR? ?
S3	393488	CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR - PCB OR SOC
S4	19659	(SECOND OR SECONDARY OR 2ND OR ANOTHER OR OTHER OR DIFFERE-NT OR SEPARATE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINATION)(2W)S3
S5	1602408	ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR A-NOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT? OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GO-OD OR CORRECT?? OR PROPER?
S6	379191	S5(10N)(DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANA-LYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND???? OR COMP-UTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7	390752	S5(10N)(GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN? OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8	115	S1:S2(20N)S4
S9	45	S8(100N)S6:S7
S10	366	S4(20N)S6:S7
S11	21	S8(100N)S10
S12	10	S11 AND AC=US/PR AND AY=(1978:2002)/PR
S13	10	S11 AND AC=US AND AY=1978:2002
S14	10	S11 AND AC=US AND AY=(1978:2002)/PR
S15	12	S11 AND PY=1978:2002
S16	17	S12:S15
S17	17	IDPAT (sorted in duplicate/non-duplicate order)